SHEET 1 OF 1

		'ΑΤ	ON DISCLOS TON IN AN JICATION	·	ATTY. DOCKET NO. 67161-149		SERIAL NO. 10/812, 403			
					APPLICANT Yasumasa TSUKAMOTO, et al.					
•	(	(PT	O-1449)	,	FILING DATE March 30, 2004	GROUP 2827				
U.S. PATENT DOCUMENTS										
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Codez (1 known)		Publication Date MM-DD-YYYY	Name of Patentee or Appli Document	cant of Cited	Page Relev	ges, Columns, Lines, Where levant Passages or Relevant Figures Appear		
		us								
		US	<del></del>			<u> </u>	+	·		
		US	<del></del>		,		-			
		US						_		
		US								
ļ <del> </del>		US	<u></u>							
		US			_		<u> </u>			
		US					+			
	<del></del>	US								
		US								
		US								
l		US	<u>-</u>	FOREIGN PA	TENT DOCUMENTS		<del>1</del> ,	<del></del>		
EXAMINER'S		Foreign Patent Document		Publication Date	Name of Patentee or	Pages, Columns, Lines		Translation	· -	
INITIALS	CITE NO.	Country Codes -Number 4 -Kind Codes (if known)		MM-DD-YYYY	Applicant of Cited Document	Where Relevant Figures Appear			<del></del>	
			11-213673	08/06/1999	MATSUSHITA ELECTRIC		<del></del>	Yes Japanese (w/ English Abstract)		1
7			09-73784	03/18/1997	NEC CORP			Japanese (w/		H
		ļ	10-178110	06/30/1998	TOSHIBA CORP			Japanese (w/ English Abstract)		
	Α		P2003-60089	02/28/2003	MITSUBISHI ELECTRIC CORP			Japanese (w/ English Abstract)		$\prod$
	A		P2001-339071	12/07/2001	MITSUBISHI ELECTRIC CORP			Japanese (w/ English Abstract)		
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)										
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.								
P		Hiroshi KAWAGUCHI et al., "DYNAMIC LEAKAGE CUT-OFF SCHEME FOR LOW-VOLTAGE SRAM's", IEEE 1998 Symposium on VLSI Circuits Digest of Technical Papers, pp. 140-141							-	
EXAMINER DATE CONSIDERED SIGN									_	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.